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ATTY. DOCKET NO.
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LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION DISCLOSURE
STATEMENT

(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT Paul Hansma, et al.

FILING DATE
9/6/96

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS IF APPROPRIATE | FILING DATE |
|------------------|-----------------|----------|-----------------|-------|-------------------------|-------------|
| | AA 4,935,634 | 6-19-90 | Hansma et al | | | |
| | AB 5,164,791 | 11-17-92 | Kubo et al. | | | |
| | AC 5,172,002 | 12-15-92 | Marshall | | | |
| | AD 5,206,702 | 4-27-93 | Kato et al. | | | |
| | AE 5,231,286 | 7-27-93 | Kajimura et al. | | | |
| | AF 5,260,824 | 11-9-93 | Okada et al. | | | |
| | AG 5,291,775 | 3-4-92 | Gamble et al. | | | |
| | AH 5,298,975 | 3-29-94 | Khoury et al. | | | |
| | AI 5,388,452 | 2-14-95 | Harp et al. | | | |
| | AJ 5,394,741 | 3-7-95 | Kajimura et al. | | | |
| | AK 5,406,833 | 4-18-95 | Yamamoto | | | |

FOREIGN PATENT DOCUMENTS

| TRANSLATION | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | YES | NO |
|-------------|-----------------|------|---------|-------|----------|-----|----|
| AL | | | | | | | |

OTHER ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

| | |
|----|--|
| AM | Drake et al.: "Imaging crystals, polymers and processes in water with the atomic force microscope," <u>Science</u> , Vol. 243, 1586 (1989) <i>(no month)</i> |
| AN | Hansma et al.: "A new, common optical-lever based atomic force microscope," <u>J.Appl.Phys.</u> , Vol. 76, 796 (1994) <i>(no month)</i> |
| AO | Clark et al.: "A high performance scanning force microscope head design," <u>Rev.Sci.Instrum.</u> , Vol. 64, No. 4, 904 (1993) <i>(no month)</i> |
| AP | Baselt, et al.: "Scanned-cantilever atomic force microscope head design," <u>Rev. Sci.Instrum.</u> , Vol 64, No. 4, 908 (1993) <i>(no month)</i> |
| AQ | Walters, et al.: "Short cantilevers for atomic force microscopy," <i>(no date)</i> |

- ✓ AR Hipp et al.: "A stand-alone scanning force and friction microscope," Ultramicroscopy, Vol 42-44, 1498-1503 (1992). (no month)
- ✓ AS Alexander, et al.: "An atomic resolution atomic-force microscope implemented using an optical lever" J. Appl. Phys., Vol. 65, 164-167 (1989) (no month)
- ✓ AT Binnig et al.: "Atomic Force Microscope" Phy.Rev.Let., Vol. 56, No. 9 (1986) (no month)
- ✓ AU Chalmers et al: "Determination of tilted superlattice structure by atomic force microscopy" Appl. Phys. Let., Vol. 55, No. 24 (1989) (no month)
- ✓ AV Dietz et al.: "Atomic Force Microscopy of C₆₀/C₇₀ Single-Crystal Fullerenes under Ethanol" Applied Phys., A.56, 207-210 (1993) (no month)
- ✓ AW Dietz et al.: "Molecular structure and thickness of highly oriented poly (tetrafluoroethylene) films measured by atomic force microscopy" J. of Materials Sci., (1993). (no month)
- ✓ AX Erlandsson et al.: "Atomic force microscopy using optical interferometry" J. Vac.Sci.Technol.(1988) (no month)
- ✓ AY Hansma et al.: "Scanning Tunneling Microscopy and Atomic Force Microscopy: Application to Biology and Technology" Science, Vol. 242, pgs. 209-242 (1988) (no month)
- ✓ AZ Hansma et al: "A new optical lever based atomic force microscope" J. Appl. Phys., Vol. 76, (1994) (no month)
- ✓ BA Hillner et al.: "AFM images of dissolution and growth on a calcite crystal" Ultramicroscopy, pgs. 1387-1393 (1992) (no month)
- ✓ BB Hillner et al.: "Combined Atomic Force and Scanning Reflection Interference Contrast Microscopy; Scanning, Vol. 17, 144-147 (1995) (no month)
- ✓ BC Hillner et al.: "Combined Atomic Force and Confocal Laser Scanning Microscope" JMSA, Vol. 1, No. 3, 127-130 (1995) (no month)
- ✓ BD Kees, et al.: "Compact stand-alone atomic force microscope," Rev. Sci.Instrum., Vol 64, No. 10, (1993) (no month)
- ✓ BE Jung, et al.: "Novel stationary sample atomic force microscope with beam tracking lens" (no date)
- ✓ BF Marti et al.: "Atomic force microscopy of liquid covered surfaces: atomic resolution images," Appl.Phys.Let., Vol 51, No. 7 (1987). (no month)
- ✓ BG Marti, et al.: "A atomic force microscopy of an organic monolayer" Science, Vol. 239(1988) (no month)

- BH Marti et al.: "Atomic resolution force microscopy of graphite and the 'native oxide' on silicon"
Dept. of Physics, UCSB, (1987) (no month)
- BI Marti et al: "Atomic force microscopy and scanning tunneling microscopy with a combination atomic force microscope/scanning tunneling microscope" J.Vac.Sci.Techol., A6(3)(1988)
 (no month)
- BJ Marti et al.: "Control electronics for atomic force microscopy" Rev.Sci.Instrum, (1988)
 (no month)
- BK Marti et al.: "Probing surfaces with the atomic force microscope" SPIE, Vol. 897 (1988).
 (no month)
- BL Meyer et al.: "Erratum: Novel optical approach to atomic force microscopy" Appl. Phys. Let.
Vol. 53 (1988) (no month)
- BM Putman et al.: "A theoretical comparison between interferometric and optical beam deflection technique for the measurement of cantilever displacement in AFM" Ultramicroscopy, pp. 1509-1513
 (1992) (no month)
- BO Putman et al: "Polymerized LB films imaged with a combined atomic force microscope-fluorescent microscope" Langmuir, Vol. 8, pp. 3014-3019 (1992)
 (no month)
- BP Putman et al.: "Immunogold labels: cell-surface markers in atomic force microscopy,"
Ultramicroscopy, Vol 48, pp. 177-182 (1993).
 (no month)
- BQ Radmacher et al.: "An AFM with integrated micro fluorescence optics: design and performance"
Ultramicroscopy, pp. 968-972 (1992)
 (no month)
- BR Ruger et al.: "Atomic force microscopy" Physics Today, (1990)
 (no month)
- BS Walters et al: "Atomic force microscope integrated with a scanning electron microscope for tip fabrication" App. Phys. Let., Vol. 65 (1994)
 (no month)
- BT Radmacher et al.: "Scanning nearfield optical microscope using microfabricated probes"
Rev.Sci.Instrum, Vol. 65 2737 (1998)
 (no month)
- BU Martin et al.: "Atomic force microscope mapping and probing on a sub-100-A scale" J.App.Phys.
 (no date)
- BV Walters et al. "Cantilevers for atomic force microscopy" UCSB, Dept. of Physics
 (no date)

EXAMINER

John R. Lee

DATE CONSIDERED

10-25-97

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.